


<b>Search Notes</b>  	<b>Application/Control No.</b>  10565106	<b>Applicant(s)/Patent Under Reexamination</b>  HAN ET AL.
	<b>Examiner</b>  M. Lee	<b>Art Unit</b>  2622

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
348	515, 518, 484	9/15/08	ml

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
east	9/15/08	ml

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

	/M. Lee/ Primary Examiner.Art Unit 2622
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